



PI3A412

0.4Ω, 3.3V, Quad SPDT Analog Switch

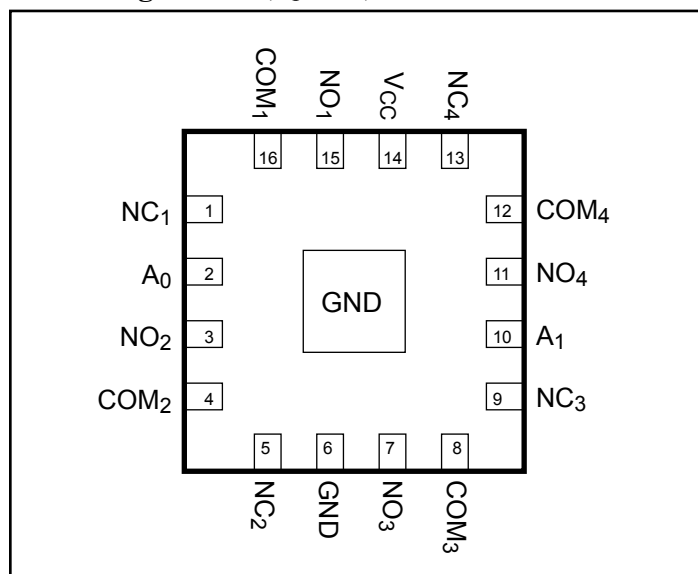
Features

- CMOS Technology for Bus and Analog Applications
- Low On-Resistance: 0.4Ω (+2.7V Supply)
- Wide V_{CC} Range: +1.6V to +4.2V ±10%
- I_{CC} = 0.3μA @ T_A = +25°C
- Rail-to-Rail switching throughout Signal Range
- Fast Switching Speed: 20ns TYP. at 3.3V
- High Off Isolation: -65dB
- Crosstalk Rejection: -65dB
- Extended Industrial Temperature Range: -40°C to 85°C
- Packaging: (Pb-free & Green)
 - 16-contact TQFN (ZL), 2.5mm x 2.5mm
 - 16-contact TQFN (ZH), 3.0mm x 3.0mm

Applications

- Cell Phones
- PDAs
- Portable Instrumentation
- Battery Powered Communications
- Computer Peripherals
- Audio & Video Signal Routing
- PCMCIA Cards
- Modems
- Hard Drives
- JTAG Testing

Pin Configuration (top view)

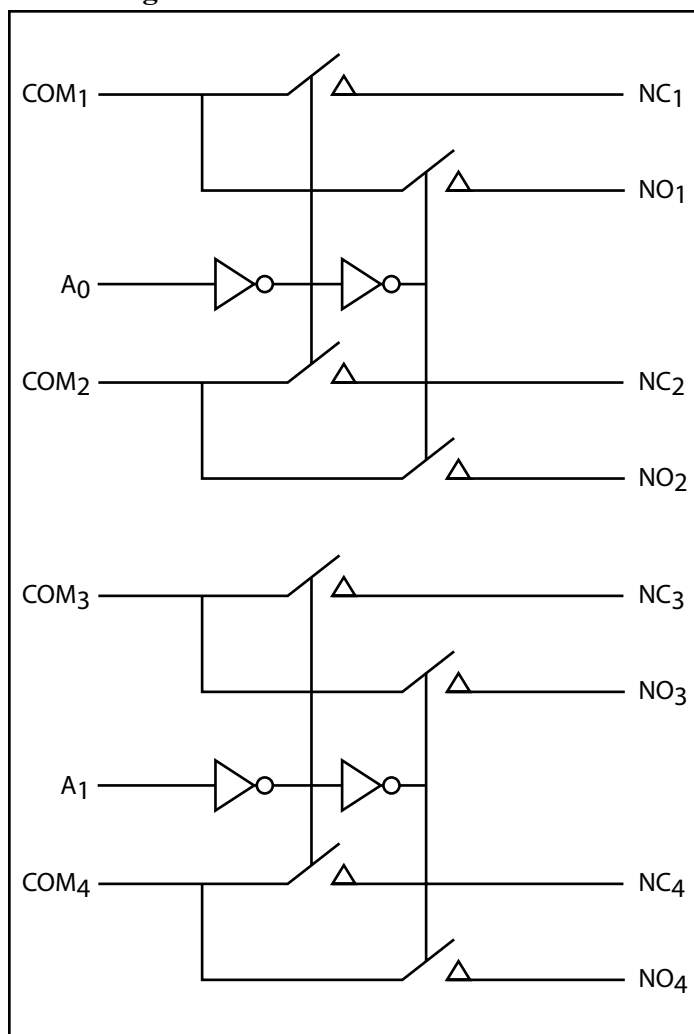


Description

The PI3A412 is a quad single-pole double-throw (SPDT) CMOS switch. It can be used as an analog switch or as a low-delay bus switch. Specified over a wide operating power supply voltage range, +1.6V to +4.2V, the switch has an On-Resistance of 0.4Ω at 2.7V.

Control inputs, Ax, tolerates input drive signals up to 5V, independent of supply voltage.

Block Diagram



**Pin Description**

Pin #	Name	Description
4, 8, 12, 16	COM _X	Common Output / Data Port
1, 5, 9, 13	NC _X	Data Port (normally connect)
3, 7, 11, 15	NO _X	Data Port (normally open)
2, 10	A ₀ , A ₁	Logic Input Control
6	GND	Ground
14	V _{CC}	Positive Power Supply

Notes :

1. X = 1, 2, 3, or 4

Function Tables

A ₀	Function	A ₁	Function
0	NC _X Connected to COM _X	0	NC _Y Connected to COM _Y
1	NO _X Connected to COM _X	1	NO _Y Connected to COM _Y

Notes :

1. X = 1 or 2
2. Y = 3 or 4

Absolute Maximum Ratings

Voltages Referenced to GND

V_{CC} 1.5V to +4.6V

V_{NOx}, V_{NCx}, V_{COMx}, V_{Ax} ⁽¹⁾ -0.5V to V₊ +0.3V
or 30mA, whichever occurs first

Current (any terminal)..... ±200mA

Peak Current, V_{NC} + V_{NO}
(Pulsed at 1ms, 10% duty cycle)..... ±400mA

Thermal Information

Continuous Power Dissipation

16-pin Thin QFN (derate 7.1mW/°C above +70°C)..... 0.5W

Storage Temperature -65°C to +150°C

Lead Temperature (soldering, 10s) +300°C

Note 1: Signals on NC, NO, COM, or A exceeding V_{CC} or GND are clamped by internal diodes. Limit forward diode current to 30mA.

Caution: Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied.



Electrical Specifications - Single +3.3V Supply

($V_{CC} = +3.3V \pm 10\%$, $GND = 0V$, $V_{IH} = 1.3V$, $V_{IL} = 0.5V$) ($T_A = -40^\circ C$ to $+85^\circ C$)

Parameter	Symbol	Conditions	Min. ⁽¹⁾	Typ. ⁽²⁾	Max. ⁽¹⁾	Units
Analog Signal Range ⁽³⁾	V_{ANALOG}		0		V_{CC}	V
On Resistance	R_{ON}	$V_{CC} = 2.7V$, $I_{COM} = 100mA$, $V_{IN} = +1.5V$		0.4	0.6	Ω
On-Resistance Match Between Channels ⁽⁴⁾	ΔR_{ON}			0.08	0.09	
On-Resistance Flatness ⁽⁵⁾	$R_{FLAT(ON)}$			0.1	0.15	
Off Leakage Current ⁽⁶⁾	I_{NC} (off) or I_{NO} (off)	$V_{CC} = 3.6V$ V_{NO} or $V_{NC} = 0.3V$, 3.3V	-400		400	nA
On Leakage Current ⁽⁶⁾	I_{COMx} (on)	$V_{CC} = 3.6V$, $V_{COMx} = 0.3V$, 3.3V	-400		400	

Notes:

1. The algebraic convention, where most negative value is a minimum and most positive is a maximum, is used in this data sheet.
2. Typical values are $T_A = 25^\circ C$, $V_{CC} = 4.2V$ unless otherwise specified.
3. Guaranteed by design.
4. $\Delta R_{ON} = R_{ON}$ match between channels
5. Flatness is defined as the difference between the maximum and minimum value of On-Resistance measured.
6. Leakage parameters are 100% tested at maximum rated hot temperature and guaranteed by correlation at $+25^\circ C$.

Electrical Specifications - Single +4.2V Supply

($V_{CC} = +4.2V \pm 10\%$, $GND = 0V$, $V_{IH} = 1.6V$, $V_{IL} = 0.7V$) ($T_A = -40^\circ C$ to $+85^\circ C$)

Parameter	Symbol	Conditions	Min. ⁽¹⁾	Typ. ⁽²⁾	Max. ⁽¹⁾	Units
Analog Signal Range ⁽³⁾	V_{ANALOG}		0		V_{CC}	V
On Resistance	R_{ON}	$V_{CC} = 4.0V$, $I_{COMx} = 100mA$, $V_{IN} = +1.5V$		0.4	0.6	Ω
On-Resistance Match Between Channels ⁽⁴⁾	ΔR_{ON}			0.08	0.09	
On-Resistance Flatness ⁽⁵⁾	$R_{FLAT(ON)}$			0.1	0.15	
Off Leakage Current ⁽⁶⁾	I_{NC} (off) or I_{NO} (off)	$V_{CC} = 4.4V$, V_{NO} or $V_{NC} = 0.3V$, 3.3V	-400		400	nA
On Leakage Current ⁽⁶⁾	I_{COMx} (on)	$V_{CC} = 4.4V$, $V_{COMx} = 0.3V$, 3.3V	-400		400	

Notes:

1. The algebraic convention, where most negative value is a minimum and most positive is a maximum, is used in this data sheet.
2. Typical values are $T_A = 25^\circ C$, $V_{CC} = 4.2V$ unless otherwise specified.
3. Guaranteed by design.
4. $\Delta R_{ON} = R_{ON}$ match between channels
5. Flatness is defined as the difference between the maximum and minimum value of On-Resistance measured.
6. Leakage parameters are 100% tested at maximum rated hot temperature and guaranteed by correlation at $+25^\circ C$.


Electrical Specifications - Single +4.2V Supply
 $(V_{CC} = +4.2V \pm 10\%, GND = 0V, V_{IH} = 1.6V, V_{IL} = 0.7V) (T_A = -40^\circ C \text{ to } +85^\circ C)$

Description	Parameter	Test Conditions	Min. ⁽¹⁾	Typ. ⁽²⁾	Max. ⁽¹⁾	Unit
Logic Input						
Input High Voltage	V _{IH}	Guaranteed logic High Level	1.6			V
Input Low Voltage	V _{IL}	Guaranteed logic Low Level			0.7	
Input Current with Voltage High	I _{AH}	V _A = 1.4V, all others = 0.5V	−1		1	μA
Input Current with Voltage Low	I _{AL}	V _A = 0.5V, all other = 1.4V	−1		1	
Dynamic						
Turn-On Time	t _{ON}	V _{CC} = 4.2V, V _{COM} = 2.0V, Figure 1 & 2		20	25	ns
Turn-Off Time	t _{OFF}			12	15	
Break-Before-Make	t _{BBM}	V _{IN} = 1.5V, R _L = 50Ω, C _L = 35pF, See Figure 3	1	12	15	
Charge Injection ⁽³⁾	Q	C _L = 1nF, V _{GEN} = 0V, R _{GEN} = 0Ω, Figure 4		100		pC
Off Isolation ⁽⁴⁾	O _{IRR}	R _L = 50Ω, f = 100kHz, Figure 5		-65		dB
Cross Talk ⁽⁵⁾	X _{TALK}	R _L = 50Ω, f = 100kHz, Figure 6		-65		
3dB Bandwidth	f _{3db}	See Test Circuit Figure 9		40		MHz
Off Capacitance	C _{NC(OFF)}	f = 1 MHz, Figure 7		50		pF
Off Capacitance	C _{NO(OFF)}			50		
On Capacitance	C _{ON}	f = 1 MHz, Figure 8		135		
Supply						
Power-Supply Range	V _{CC}		1.5		4.4	V
Positve Supply Current	I _{CC}	V _{CC} = 4.2V, V _A = 0V or V _{CC}		0.5		μA

Notes:

1. The algebraic convention, where most negative value is a minimum and most positive is a maximum, is used in this data sheet.
2. Typical values are $T_A = 25^\circ C$, $V_{CC} = 4.2V$ unless otherwise specified.
3. Guaranteed by design.
4. Off Isolation = $20\log_{10} [(V_{NO} \text{ or } V_{NC}) / V_{COM}]$. See Figure 5.
5. Between any two switches. See Figure 6.

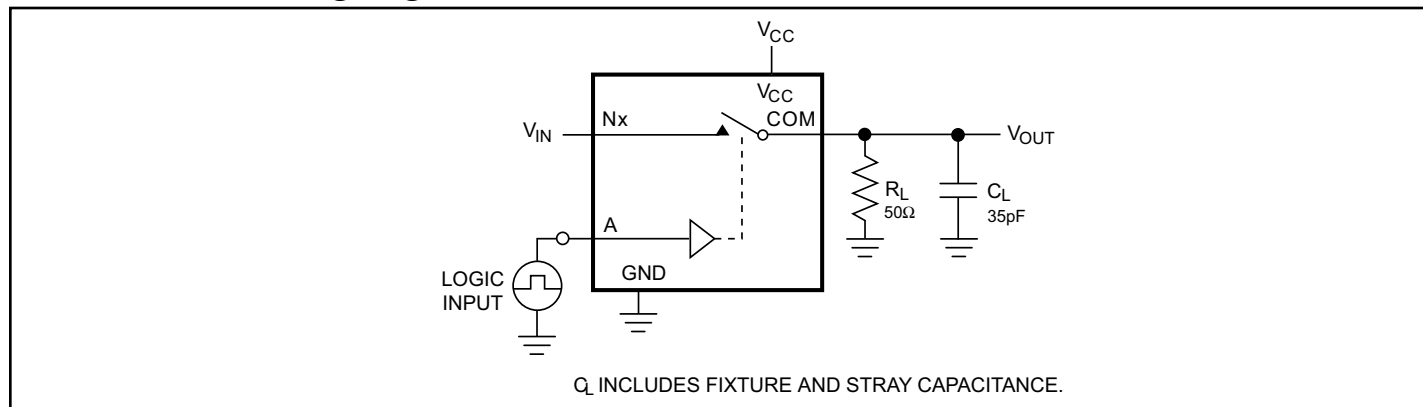

Electrical Specifications - Single +3.3V Supply
 $(V_{CC} = +3.3V \pm 10\%, GND = 0V, V_{IH} = 1.3V, V_{IL} = 0.5V) (T_A = -40^\circ C \text{ to } +85^\circ C)$

Description	Parameters	Test Conditions	Min. ⁽¹⁾	Typ. ⁽²⁾	Max. ⁽¹⁾	Units
Logic Input						
Input High Voltage	V _{IH}	Guaranteed logic High Level	1.3			V
Input Low Voltage	V _{IL}	Guaranteed logic Low Level			0.5	
Input Current with Voltage High	I _{AH}	V _A = 1.4V, all others = 0.5V	−1		1	μA
Input Current with Voltage Low	I _{AL}	V _A = 0.5V, all other = 1.4V	−1		1	
Dynamic						
Turn-On Time	t _{ON}	V _{CC} = 3.3V, V _{COM} = 2.0V, Figure 1 & 2		20	25	ns
Turn-Off Time	t _{OFF}			12	15	
Break-Before-Make	t _{BBM}	V _{IN} = 1.5V, R _L = 50Ω, C _L = 35pF, See Figure 3	1	12	15	
Charge Injection ⁽³⁾	Q	C _L = 1nF, V _{GEN} = 0V, R _{GEN} = 0Ω, Figure 4		100		pC
Off Isolation ⁽⁴⁾	O _{IRR}	R _L = 50Ω, f = 100kHz, Figure 5		-65		dB
Cross Talk ⁽⁵⁾	X _{TALK}	R _L = 50Ω, f = 100kHz, Figure 6		-65		
3dB Bandwidth	f _{3db}	See Test Circiut Figure 9		40		MHz
Off Capacitance	C _{N(COFF)}	f = 1 MHz, Figure 7		50		pF
Off Capacitance	C _{N(OFF)}			50		
On Capacitance	C _{ON}	f = 1 MHz, Figure 8		135		

Notes:

1. The algebraic convention, where most negative value is a minimum and most positive is a maximum, is used in this data sheet.
2. Typical values are $V_{CC} = 4.2V$ unless otherwise specified.
3. Guaranteed by design.
4. Off Isolation = $20\log_{10} [(V_{NO} \text{ or } V_{NC}) / V_{COM}]$. See Figure 5.
5. Between any two switches. See Figure 6.

Test Circuits and Timing Diagrams



Notes:

Unused Nx inputs must be grounded.

Figure 1. AC Test Circuit

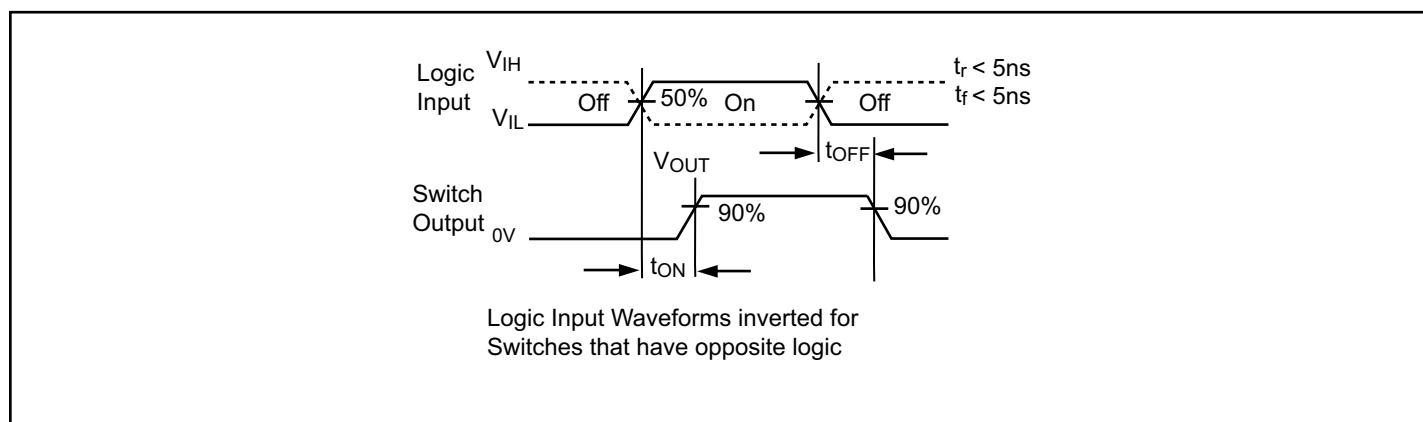


Figure 2. AC Waveforms

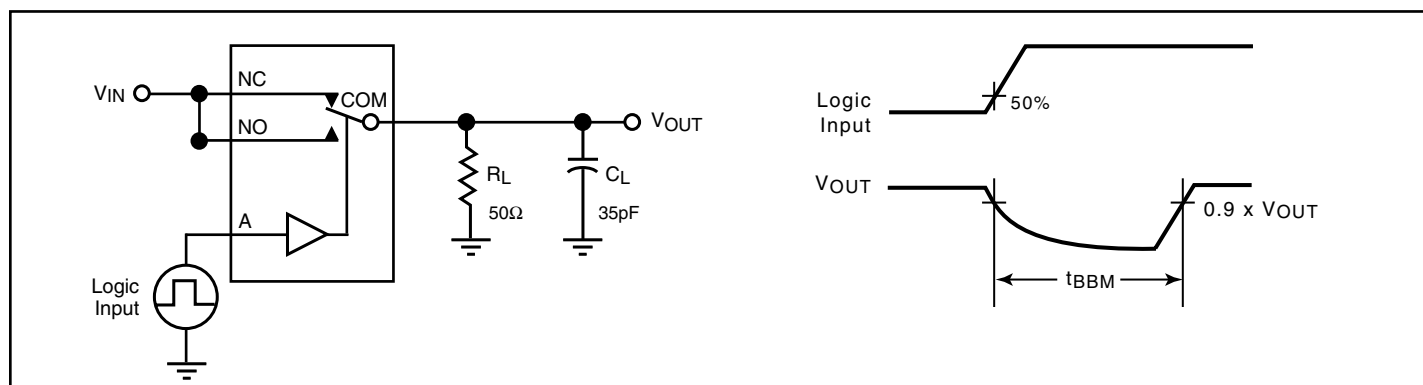
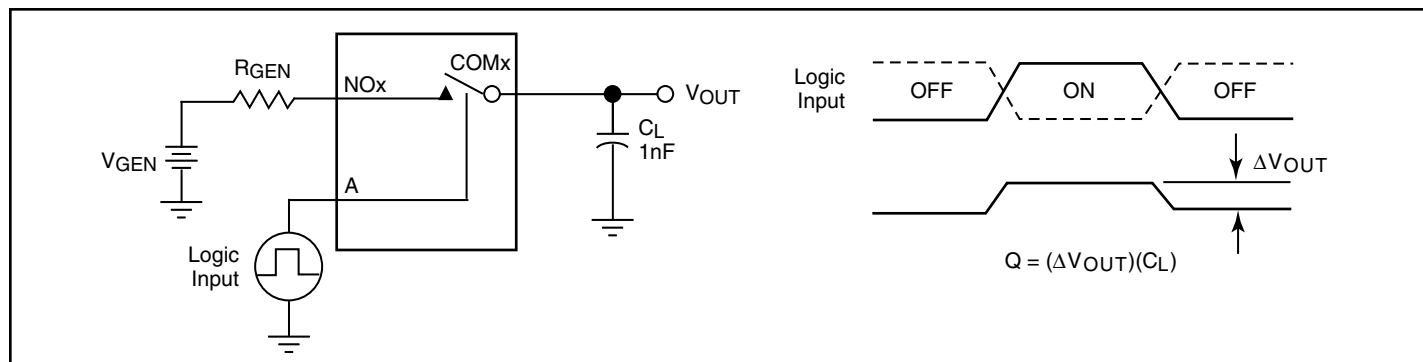
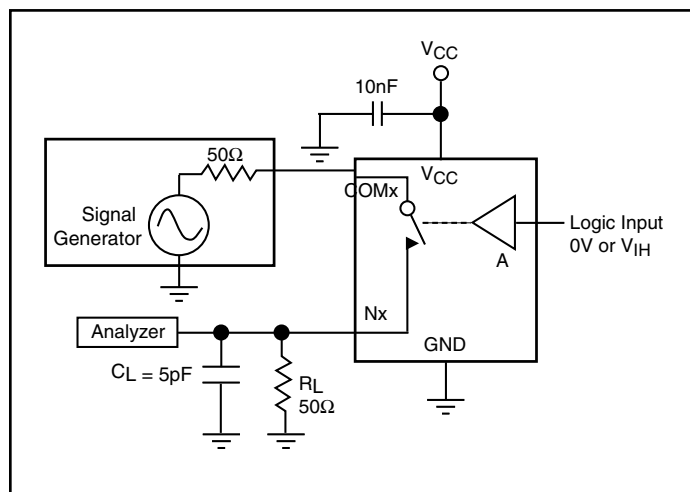
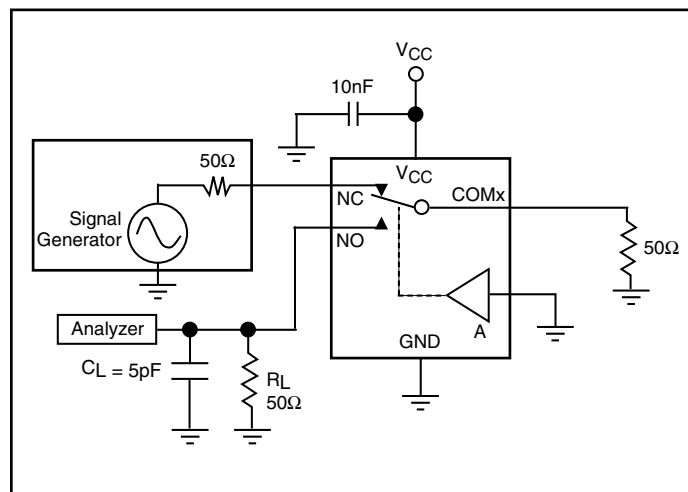
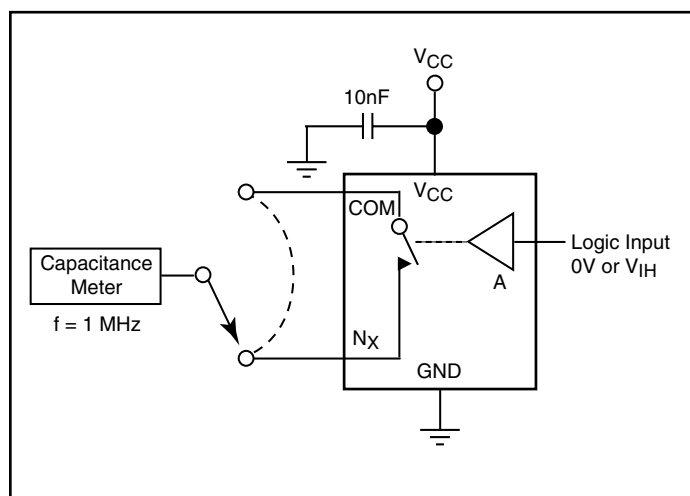
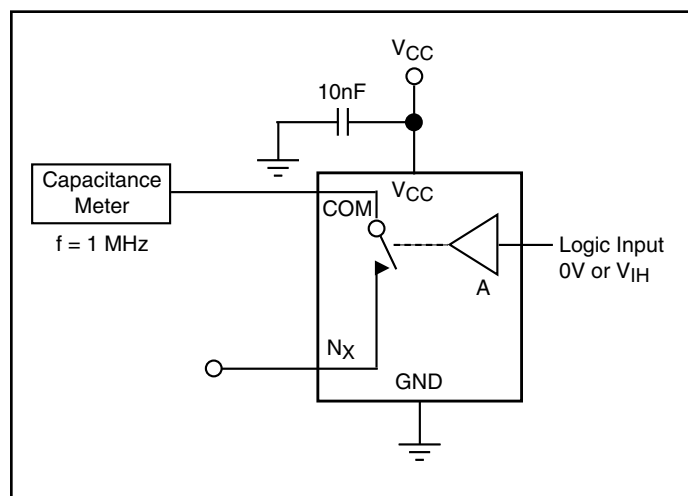
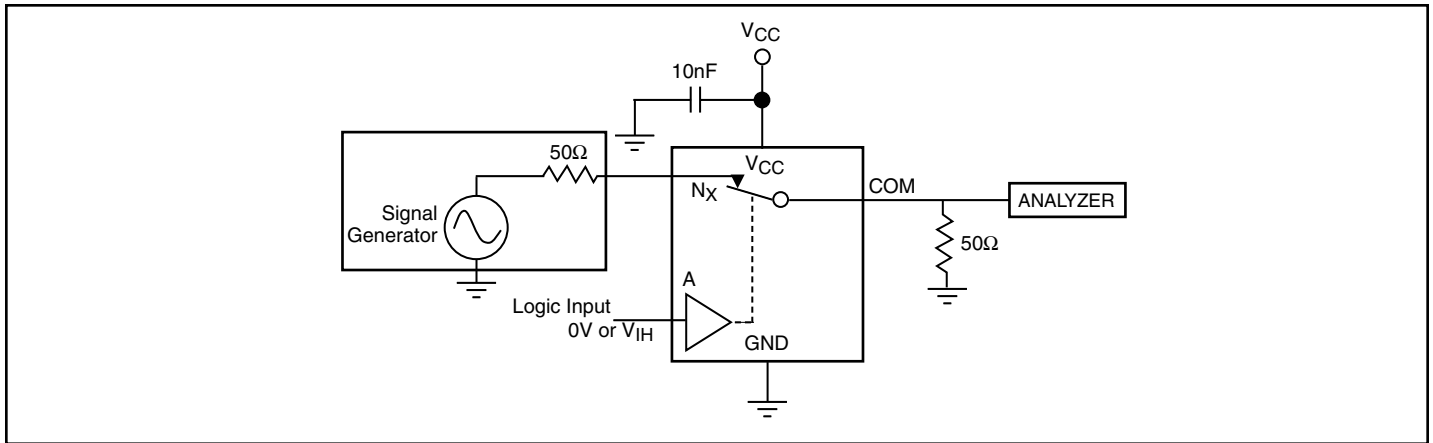
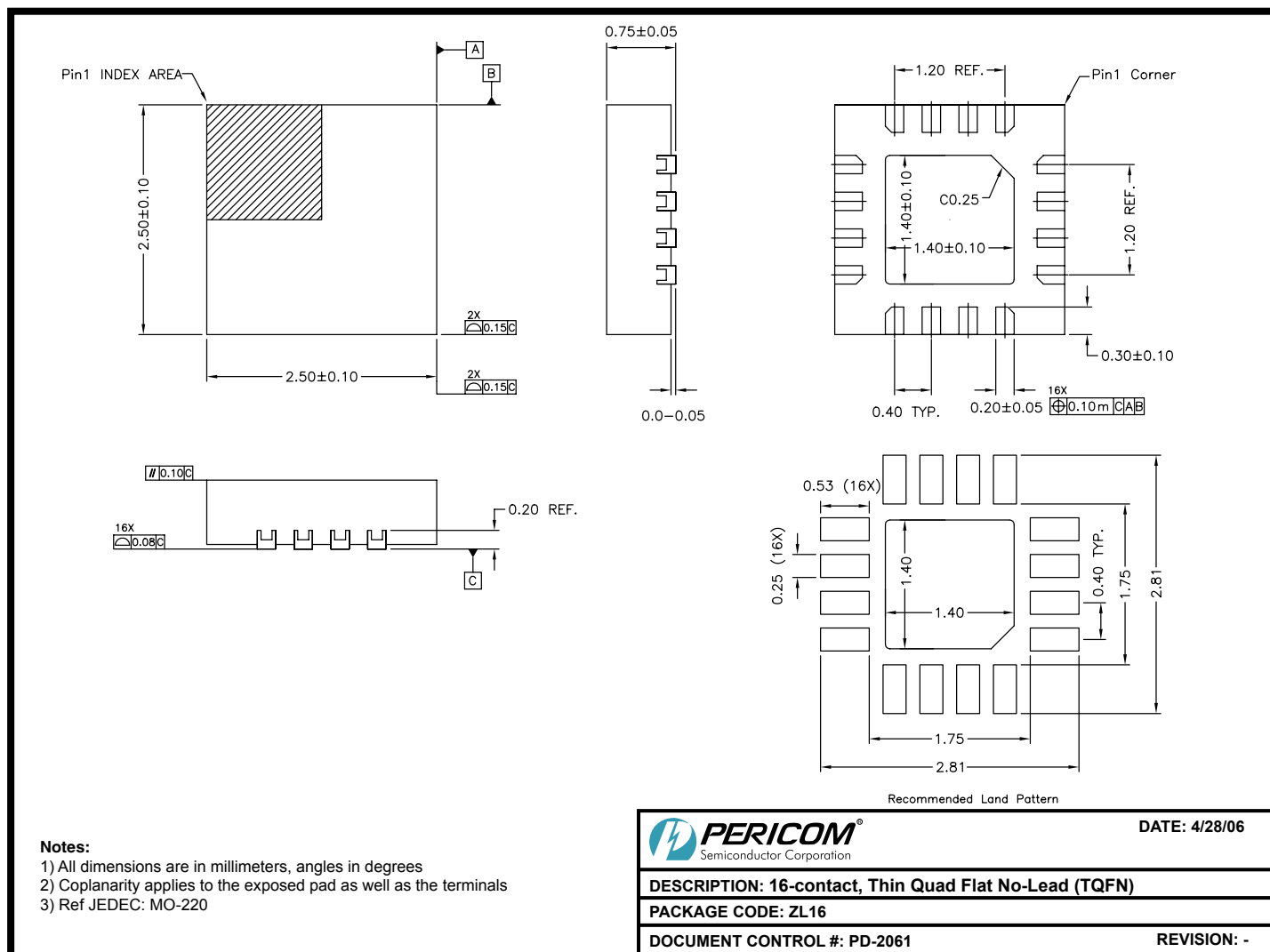
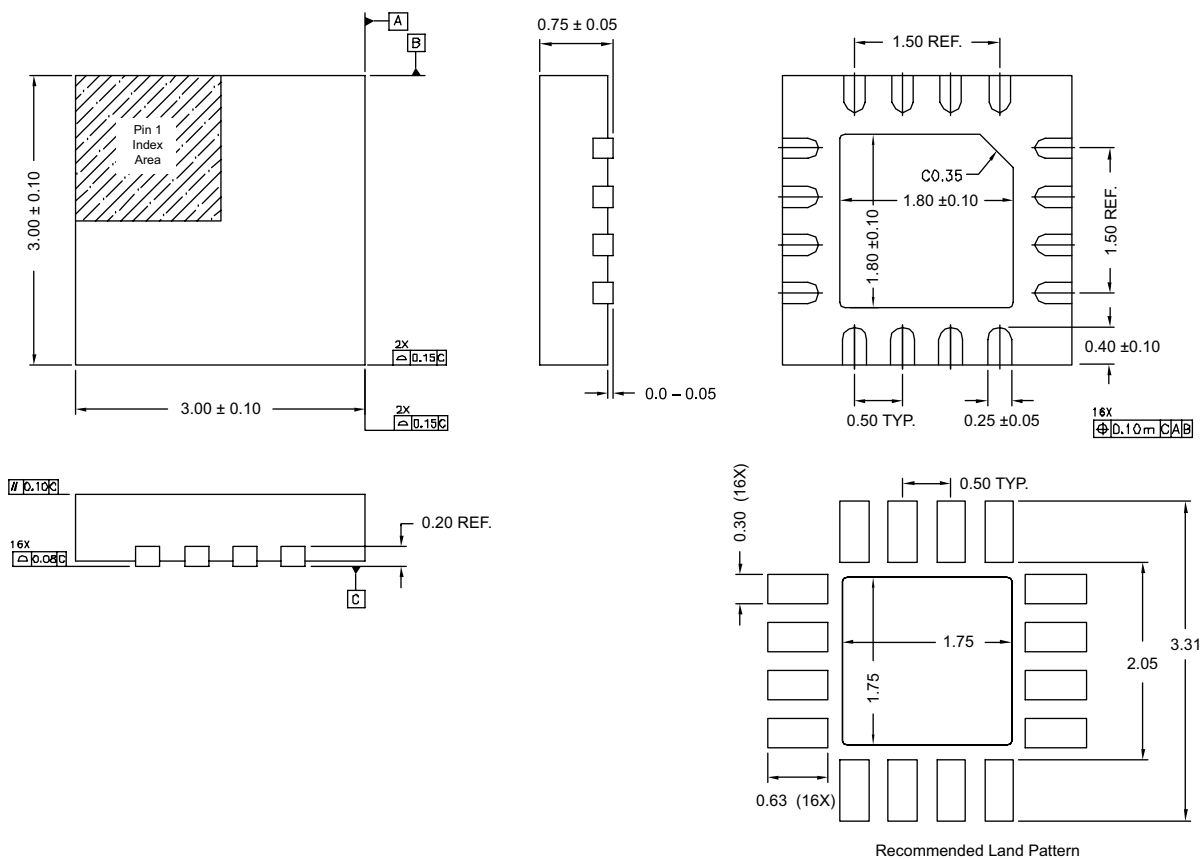


Figure 3. Break Before Make Interval Timing

**Figure 4. Charge Injection Test****Figure 5. Off Isolation****Figure 6. Crosstalk****Figure 7. Channel Off Capacitance****Figure 8. Channel On Capacitance**

**Figure 9. Bandwidth**



**Notes:**

- 1) All dimensions are in millimeters
- 2) Ref JEDEC: MO-220J (WEED)
- 3) Bilateral coplanarity zone applies to the exposed heat sink slug as well as the terminals



DATE: 03/16/06

DESCRIPTION: 16-Contact, Thin Fine Pitch Quad Flat No-Lead (TQFN)

PACKAGE CODE: ZH (ZH16)

DOCUMENT CONTROL #: PD-2047

REVISION: A

**Ordering Information**

Ordering Code	Package Code	Package Description
PI3A412ZLE	ZL	Pb-free & Green, 16-contact TQFN
PI3A412ZHE	ZH	Pb-free & Green, 16-contact TQFN

Notes:

- Thermal characteristics can be found on the company web site at www.pericom.com/packaging/
- E = Lead-free and Green Packaging
- Adding X suffix = Tape/Reel